

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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Status: Engineering

Features:

• V_{DS}, 100 V

• Maximum R_{DS(on)}, 7 mΩ

• I_D, 16 A

Applications:

• Open Rack Server Architectures

LiDAR/Pulsed Power Applications

USB-C

Isolated Power Supplies

Point of Load Converters

Class D Audio

LED Lighting

Low Inductance Motor Drive



EPC2045 eGaN® FETs are supplied in passivated die form with solder bumps.

Die Size: 2.5 mm x 1.5 mm

	Maximum Ratings			
V _{DS}	Drain-to-Source Voltage (Continuous)	100	V	
- 03	Drain-to-Source Voltage (up to 10,000 5ms pulses at 150°C)	120	,	
I _D	Continuous (T _A = 25°C, R _{BJA} = 38 °C/W)	16		
	Pulsed (25°C, T _{PULSE} = 300 μs)	130	Α	
V_{GS}	Gate-to-Source Voltage	6	.,	
V GS	Gate-to-Source Voltage	-4	V	
Tı	Operating Temperature	-40 to 150	°C	
T_{STG}	Storage Temperature	-40 to 150 °C		

	Static Characteristics (T _i = 25°C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}, I_D = 0.3 \text{ mA}$	100			V
I _{DSS}	Drain Source Leakage	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$		0.1	0.25	mA
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		1	5	mA
I _{GSS}	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		0.1	0.25	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 5$ mA	0.8	1.5	2.5	V
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 16 \text{ A}$	·	5.6	7	m $Ω$
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5 A$, $V_{GS} = 0 V$		1.9		V

All measurements were done with substrate shorted to source.

	Thermal Characteristics				
		TYP	UNIT		
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	°C/W		
$R_{\theta JB}$	Thermal Resistance, Junction to Board	8.5	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	64	°C/W		

Note 1: R_{mA} is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details.



	Dynamic Characteristics (T _J = 25°C unless otherwise stated)					
P/	ARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance			570	685	
C _{RSS}	Reverse Transfer Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}$		5		
C _{oss}	Output Capacitance			260	390	
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (note 2)	$V_{DS} = 0$ to 50 V, $V_{GS} = 0$ V		320		рF
C _{OSS(TR)}	Effective Output Capacitance, Time Related (note 3)	V DS - U 10 30 V, V GS - U V		420		
R_{G}	Gate Resistance			0.6		Ω
Q _G	Total Gate Charge	$V_{DS} = 50 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 16 \text{ A}$		5.2	6.5	
Q _{GS}	Gate-to-Source Charge			1.7		
Q_{GD}	Gate-to-Drain Charge	$V_{DS} = 50 \text{ V}, I_{D} = 16 \text{ A}$		1.1		
$Q_{G(TH)}$	Gate Charge at Threshold			1.2		nC
Q _{oss}	Output Charge	V _{DS} = 50 V, V _{GS} = 0 V		21	32	
Q_{RR}	Source-Drain Recovery Charge			0		

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}. Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DS}. All measurements were done with substrate shorted to source.

Figure 1: Typical Output Characteristics at 25°C

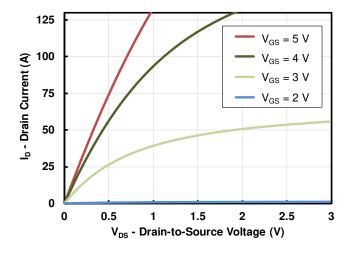
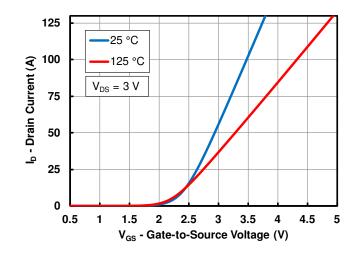


Figure 2: Transfer Characteristics



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Figure 3: R_{DS(on)} vs V_{GS} for Various Drain Currents

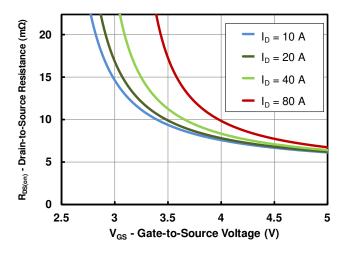


Figure 5a: Capacitance (Linear Scale)

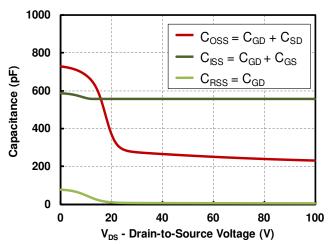


Figure 5c: Output Charge and Coss Stored Energy

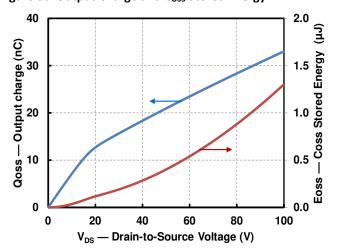


Figure 4: R_{DS(on)} vs V_{GS} for Various Temperatures

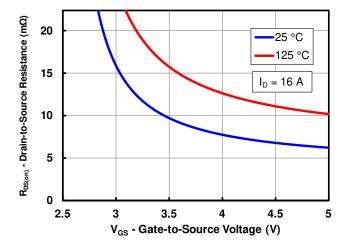


Figure 5b: Capacitance (Log Scale)

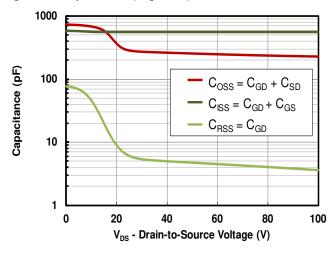


Figure 6: Gate Charge

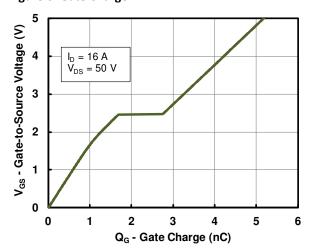




Figure 7: Reverse Drain-Source Characteristics

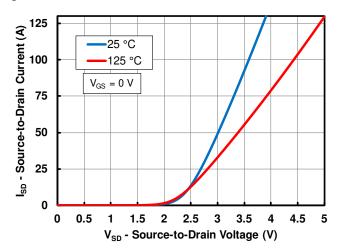


Figure 9: Normalized Threshold Voltage vs Temperature

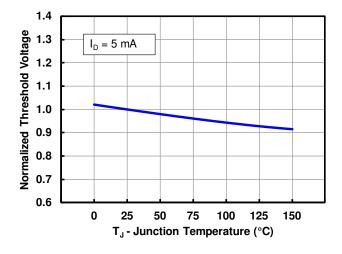


Figure 8: Normalized On-State Resistance vs Temperature

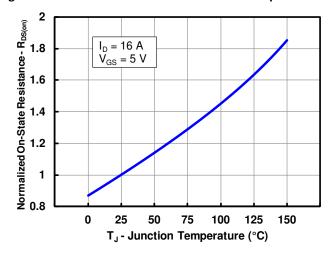


Figure 10: Safe Operating Area

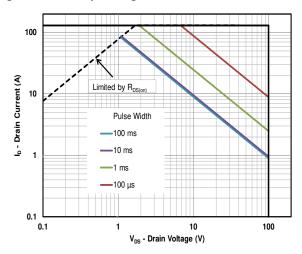
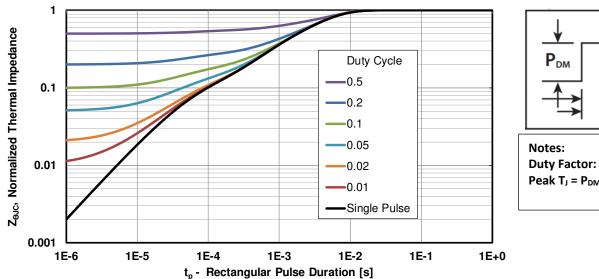


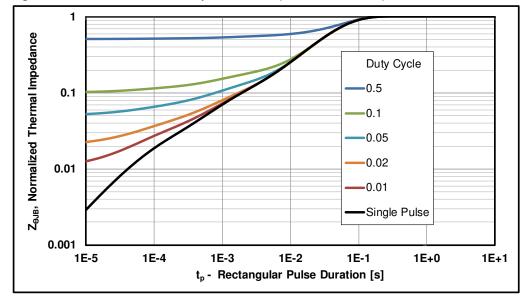


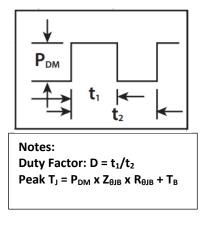
Figure 11a: Transient Thermal Response Curves (Junction-to-Case)



Notes:
Duty Factor: $D = t_1/t_2$ Peak $T_J = P_{DM} \times Z_{\theta JC} \times R_{\theta JC} + T_C$

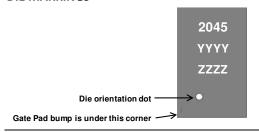
Figure 11b: Transient Thermal Response Curves (Junction-to-Board)





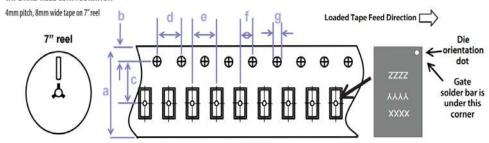


DIE MARKINGS



	Laser Marking		
Part Number	Part #	Lot_Date Code	Lot_Date Code
	Marking Line 1	Marking Line 2	Marking Line 3
EPC2045ENGRT	2045	YYYY	ZZZZ

TAPE AND REEL CONFIGURATION



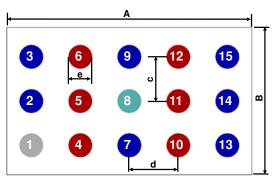
Die is placed into pocket solder bar side down (face side down)

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/IEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket,
not the pocket hole.

DIE OUTLINE

Solder Bar View



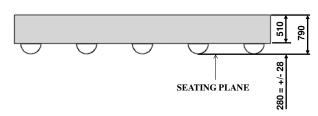
5.54	MICROMETERS			
DIM	MIN	Nominal	MAX	
Α	2470	2500	2530	
В	1470	1500	1530	
С		450		
d		500		
е	238	264	290	

Pads 1 is Gate;

Pads 2, 3, 7, 9, 13, 14, 15 are Source; Pads 4, 5, 6, 10, 11, 12 are Drain;

Pad 8 is substrate

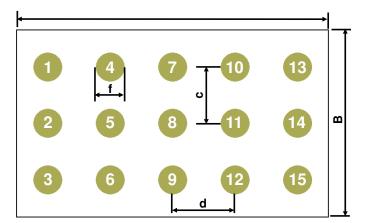
Side View





RECOMMENDED LAND PATTERN

(measurements in µm)



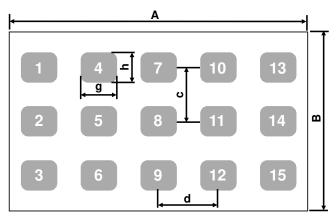
The land pattern is solder mask defined Solder mask is 10µm smaller per side than bump

DIM MICROMETER	
Α	2500
В	1500
С	450
d	500
f	230

Pads 1 is Gate; Pads 2, 3, 7, 9, 13, 14, 15 are Source; Pads 4, 5, 6, 10, 11, 12 are Drain; Pad 8 is substrate

RECOMMENDED STENCIL DRAWING

(measurements in µm)



	DIM	MICROMETERS
	Α	2500
	В	1500
	С	450
	d	500
	g	300
Ī	h	250

Recommended stencil should be 4mil (100 μ m) thick, must be laser cut, openings per drawing.

The corner has a radius of R60

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at epcco.com/epc/DesignSupport/AssemblyBasics.aspx

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